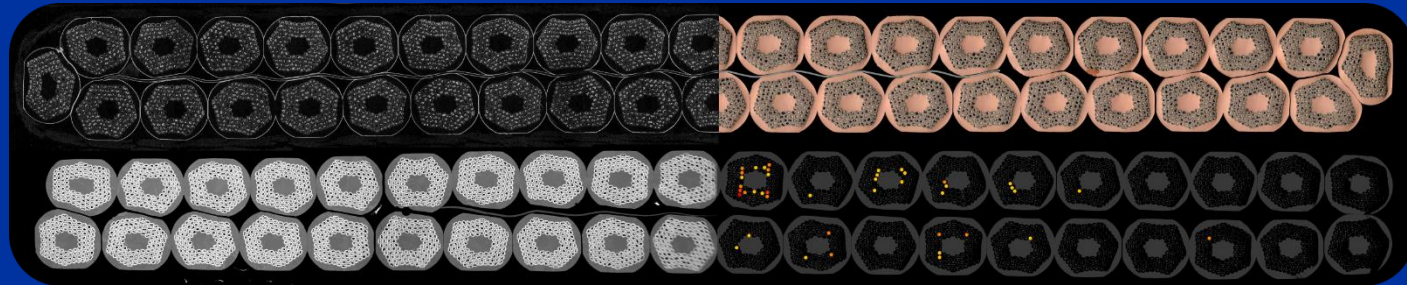


The trade-off between electrical behaviour and mechanical performance under transverse compression of Nb₃Sn conductor by varying heat treatment duration.

Kirtana Puthran

Bentejui M Clavijo, Christian Barth, Tabea Arndt, Amalia Ballarino

ICMC 2024, Geneva.

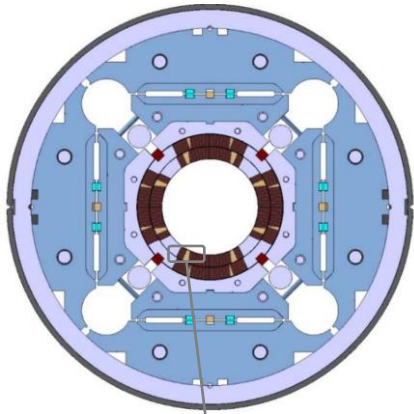


- Introduction to the Nb₃Sn cable
- Motivation
- Characterisation of mechanical behaviour
- Characterisation of electrical behaviour
- Discussion and Summary

Introduction

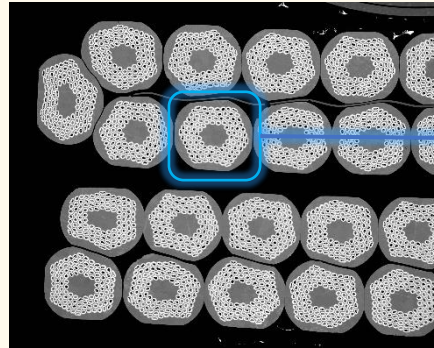
Sub-Scales of a Nb₃Sn Rutherford cable

Cross-section of the Nb₃Sn Quadrupole magnet MQXF



Unreacted Nb₃Sn Rutherford cable, with S2 fibre glass insulation

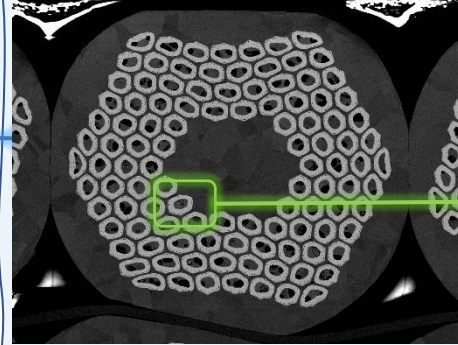
CABLE



Section of reacted double stacked cables

- 18.15 mm x 1.525 mm
- 0.4° keystone angle
- 40x 0.85 mm strands
- 12 mm x 25 µm Stainless steel core
- 145 µm S2-glass sleeve
- Impregnation resin

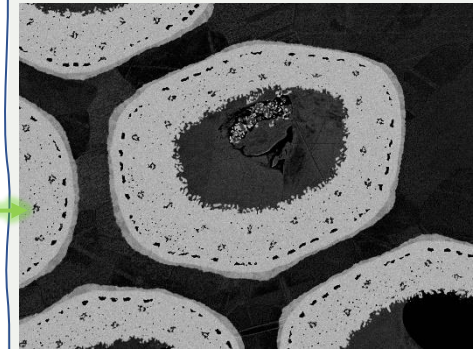
STRAND



Strand/wire in a cable

- 0.85 mm
- RRP® architecture
- 108 subelements
- Cu core
- Cu matrix

SUBELEMENT



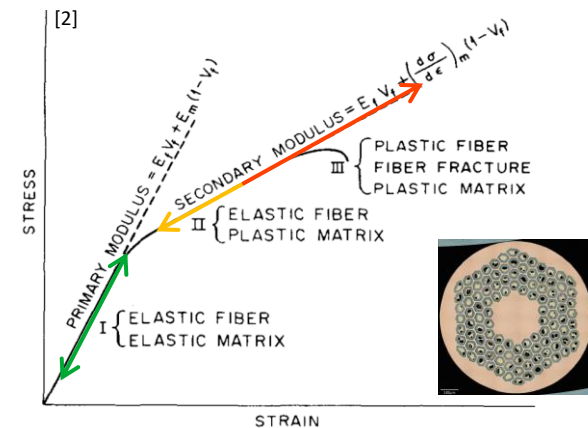
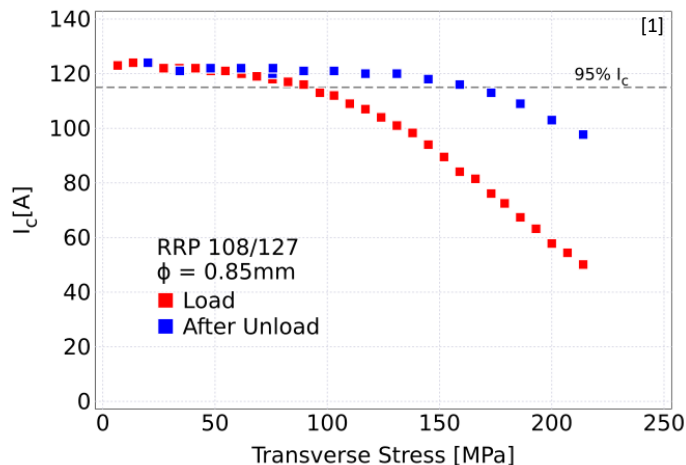
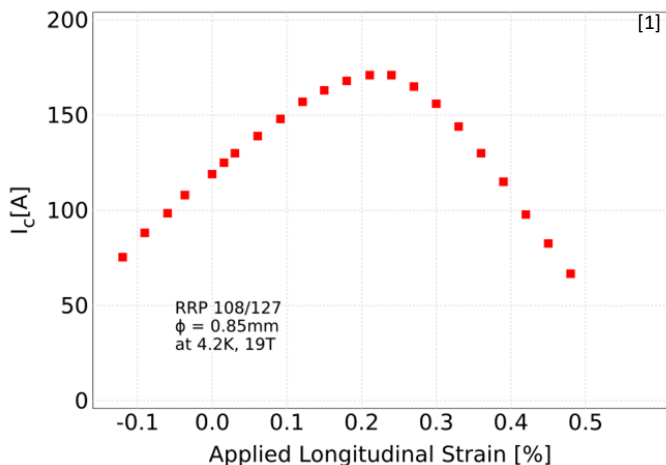
Subelement in a strand

- 0.045 mm
- CuSn core
- Ti doping rods
- **Brittle Nb₃Sn layer**
- Nb barrier
- Voids

Complex composite structure at different scales

Motivation

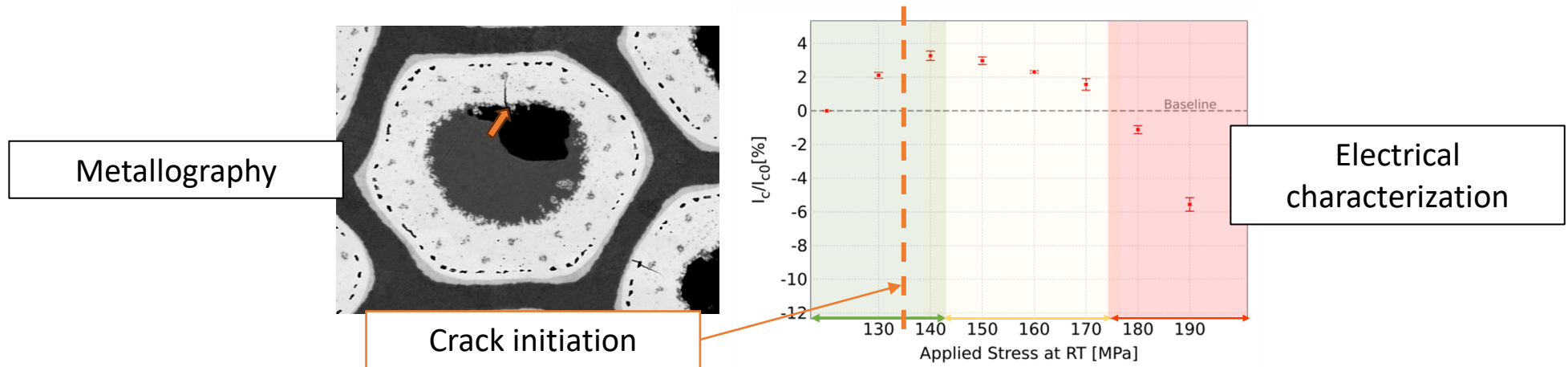
- The electrical performance of Nb₃Sn is highly sensitive to stress.



- Transverse compressive stress are the highest loads on the superconductor during operation of large accelerator magnets.

Motivation

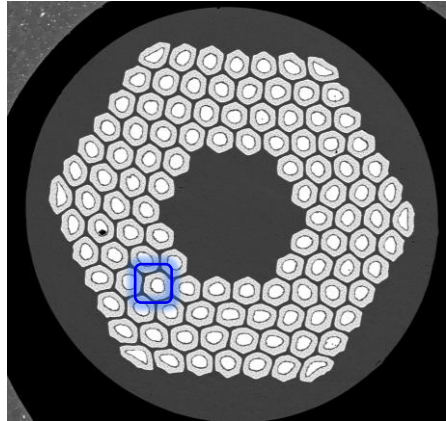
- From a previous study^[1], it has been shown that mechanical degradation in the superconductor precludes electrical degradation.



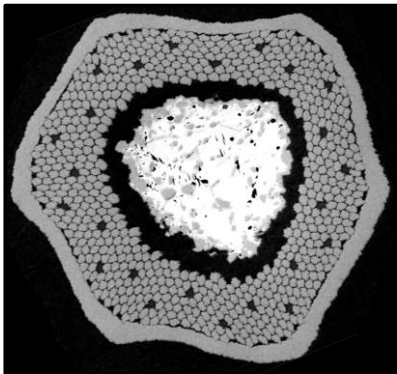
- The over-arching goal of this work is to study and propose a combination of parameters to improve the electro-mechanical robustness of the cables, by a combination in the heat treatment duration and/or impregnation resins for future high field magnets.
- Today's talk : Impact of heat treatment duration.

Reaction Heat Treatment Cycle

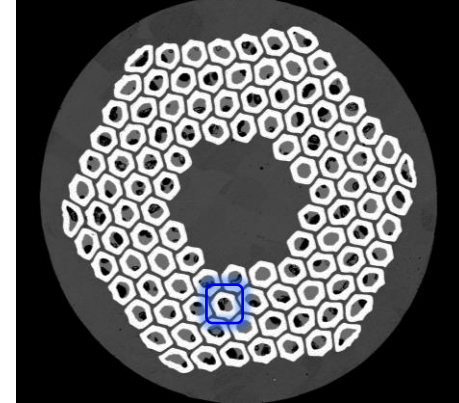
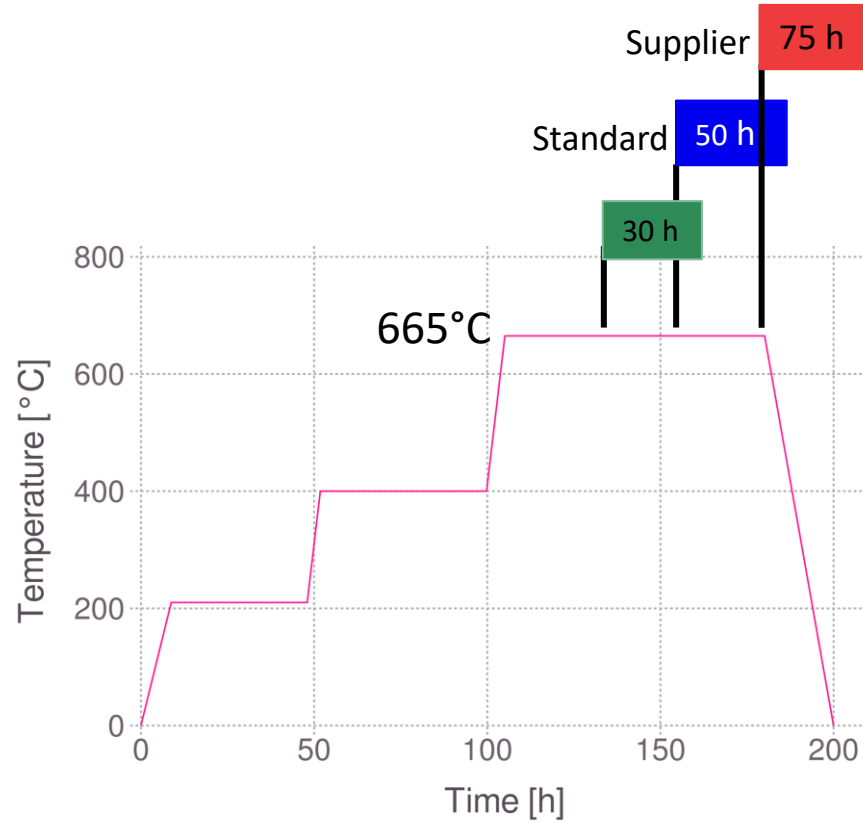
Overview



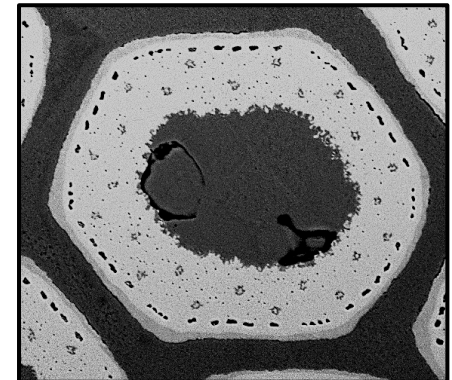
SEM micrograph – virgin RRP® 108/127
0.85 mm unreacted strand



SEM micrograph – RRP® 108/127
unreacted subelement



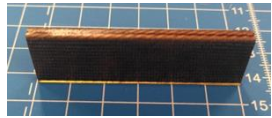
SEM micrograph – virgin RRP® 108/127
0.85 mm reacted strand



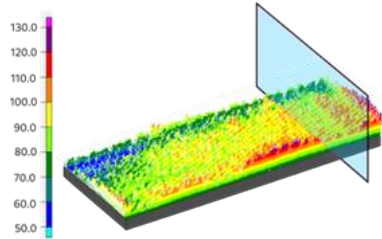
SEM micrograph – RRP® 108/127
reacted subelement

Metallographic characterisation

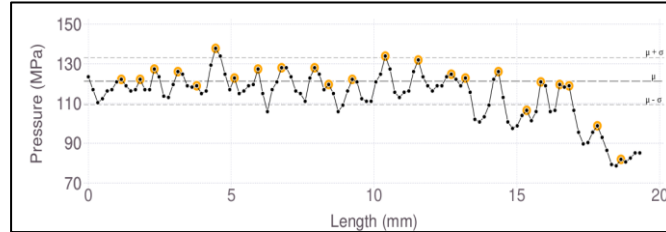
Damage mapping in compressed double-stack cable specimens



Double-stack cable sample



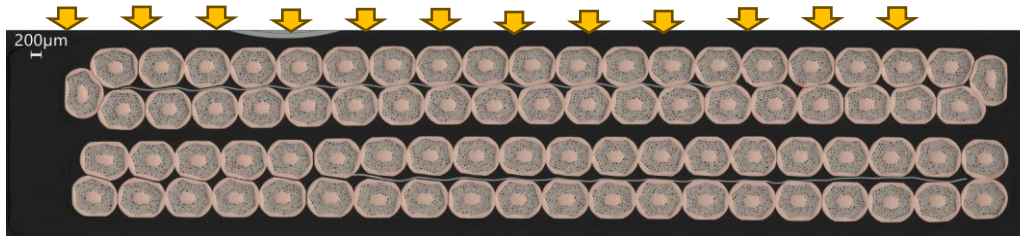
Compression map on surface



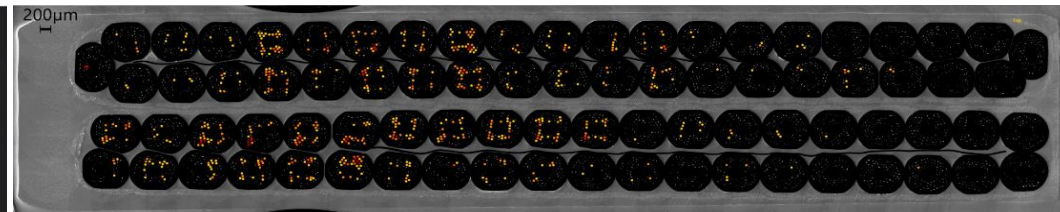
Stress distribution along the cross section.



Embedded *specimens* – transverse cross sections



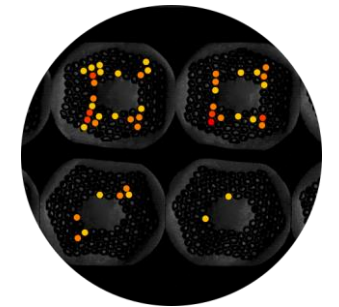
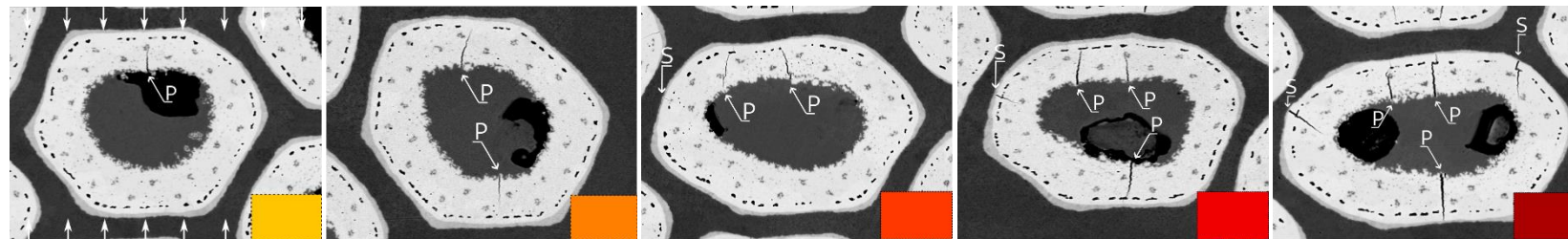
Micrograph of a transverse cross section - with an optical microscope



Damage mapping in a compressed double stack cable specimen

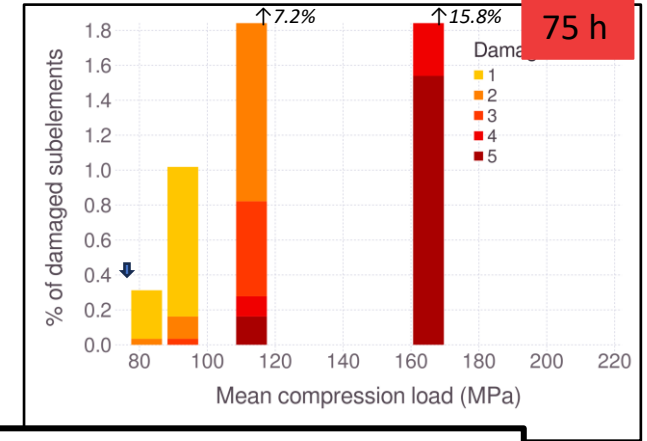
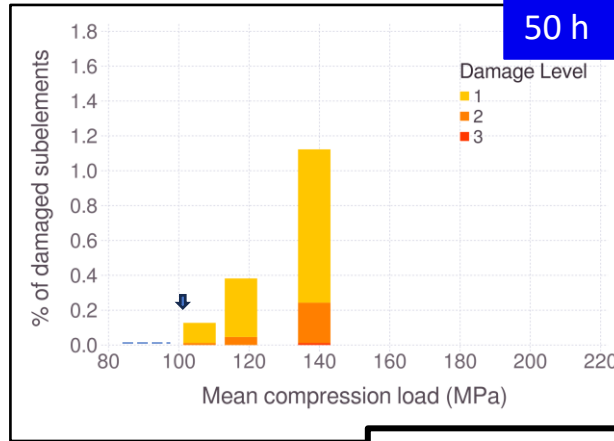
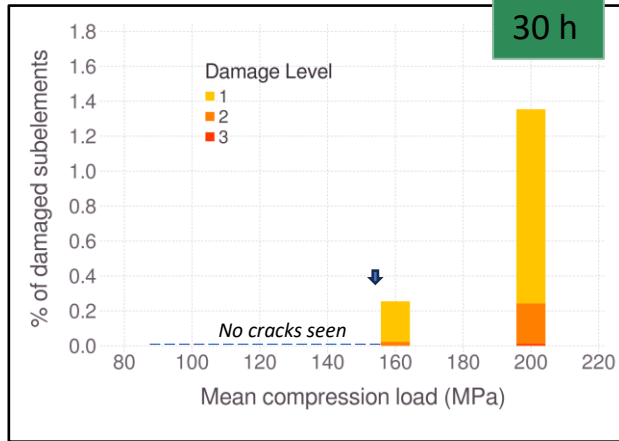
SEM Micrographs (75h) :

→ Increasing damage levels →

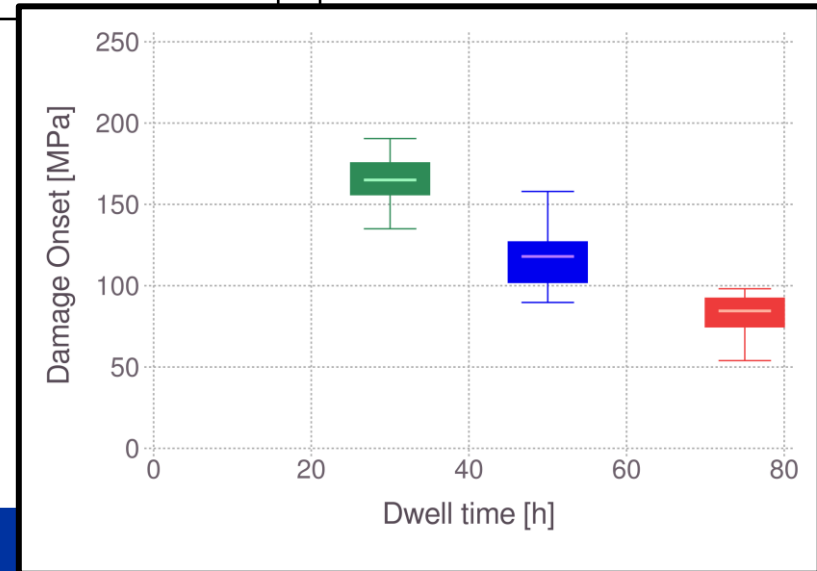


Onset and evolution of damage

Damage mapping in compressed double-stack cable specimens



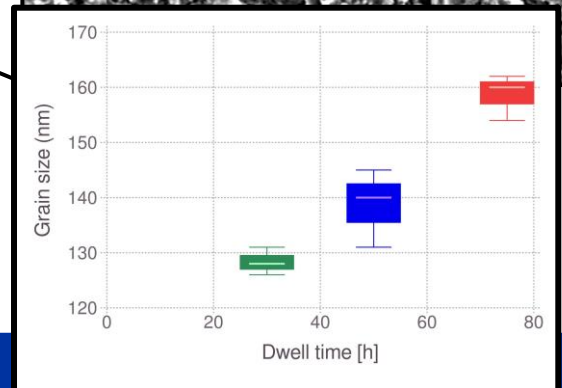
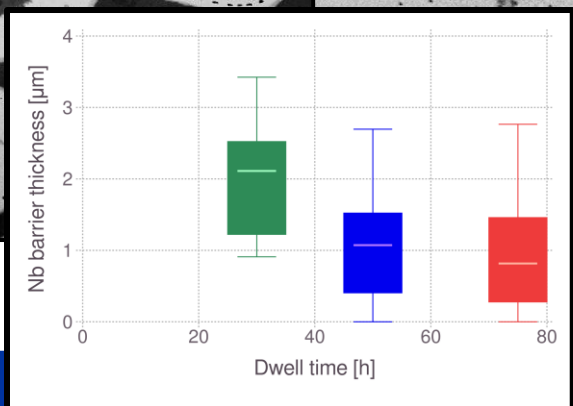
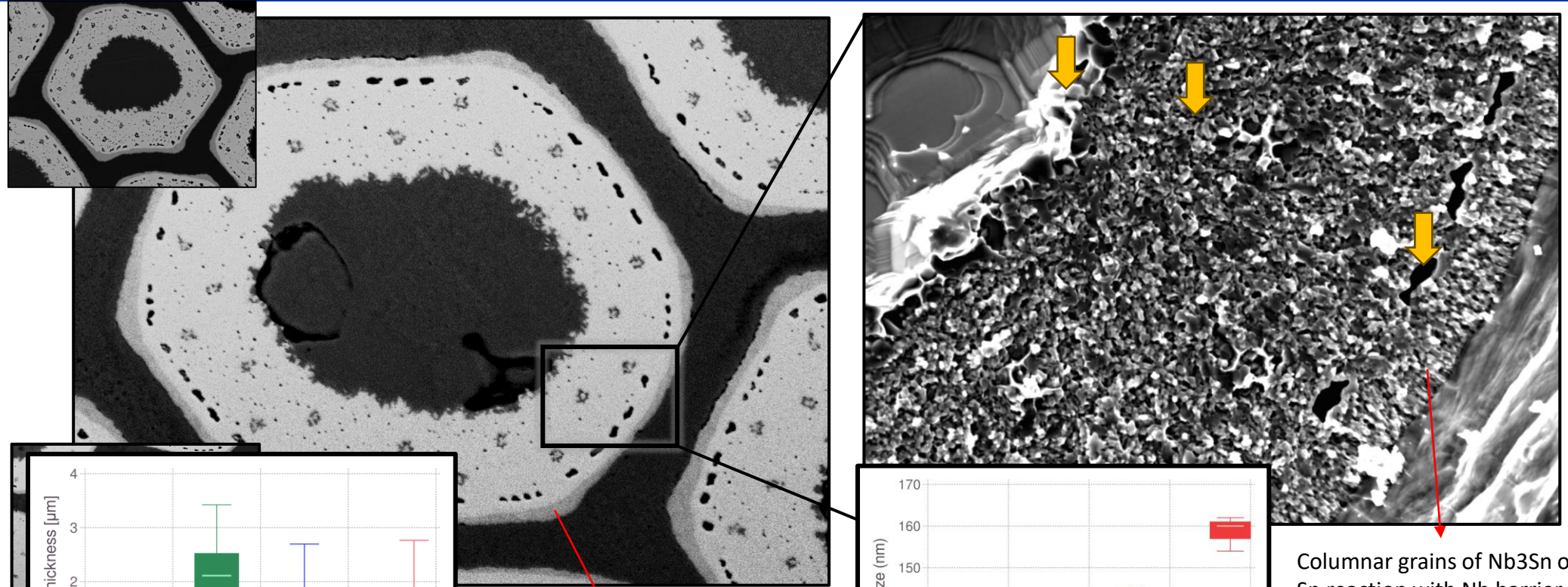
1. Damage onset threshold decreases with longer HT duration.
2. Rate of damage evolution is higher for longer heat treatment.



Observations made on over 320 wires (x108 subelements) per HT case

Microstructure

Size of the Niobium barrier and grain size of A15 phase

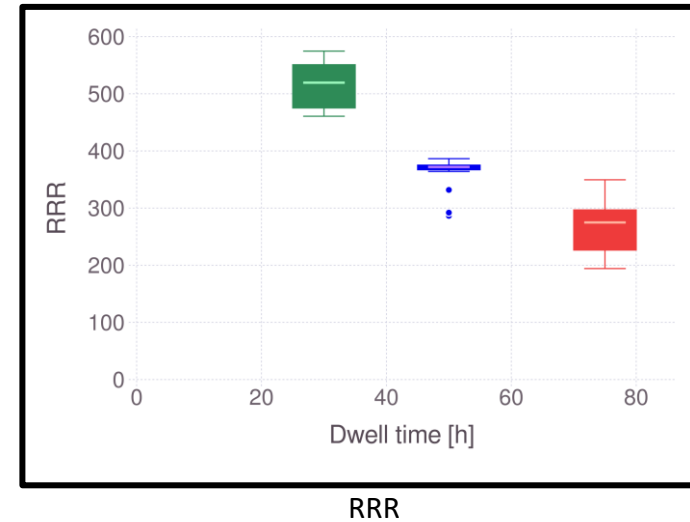
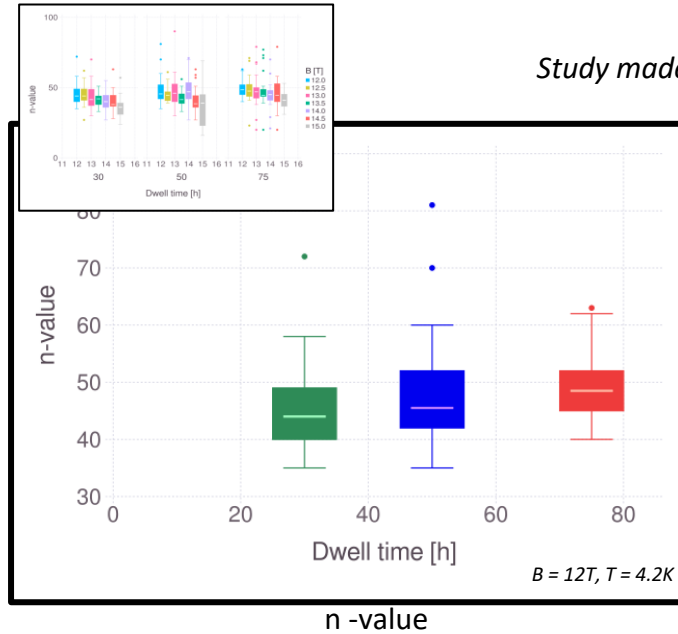
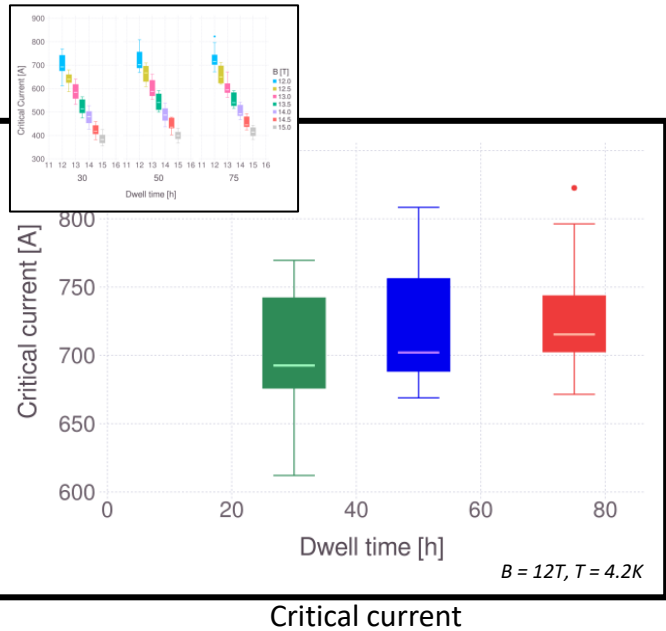


Columnar grains of Nb₃Sn of Sn reaction with Nb barrier

Variation in electrical properties

A small-scale statistical data-set

Study made on over 15 wires per HT case



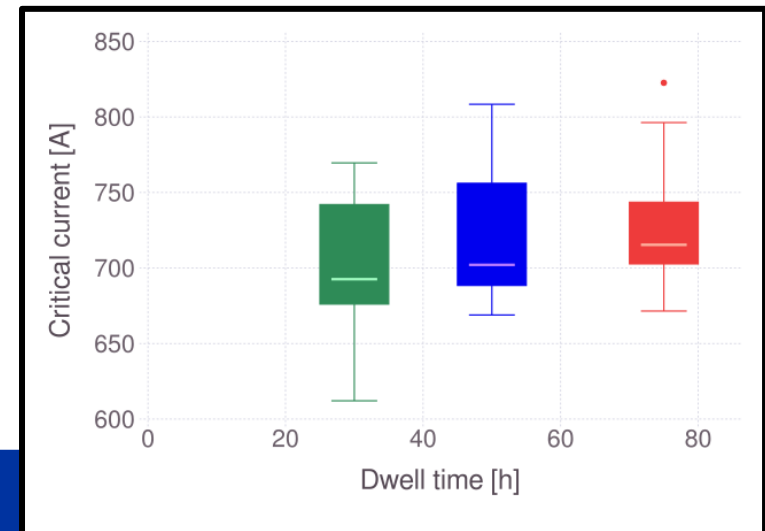
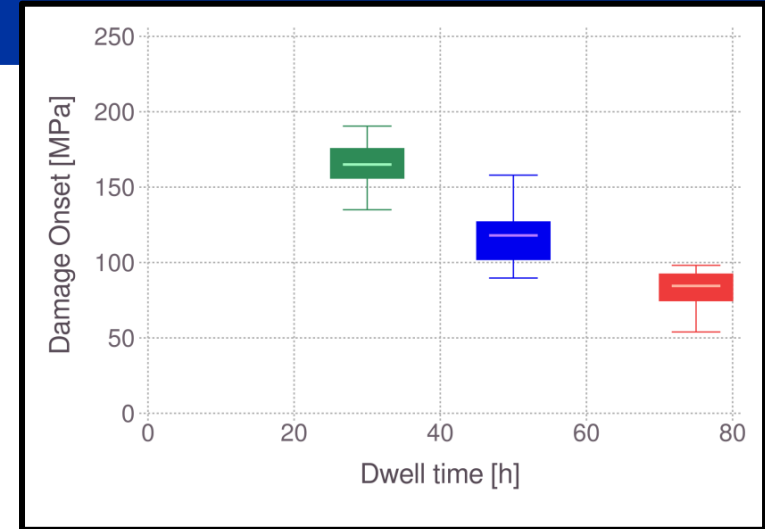
1. Critical current and n-value increases with longer heat treatment duration, due to consumption of Nb barrier into Nb_3Sn .
2. RRR or purity of Cu matrix decreases with longer heat treatment duration, due to Sn leakage into Cu matrix.

Discussion

Trade-off in the electrical and mechanical properties

Compared to standard RHT – **50h**

	30h	75h
σ_c	↑ 49%	↓ 33%
I_c (12T)	↓ 1.7%	↑ 1.5%
RRR	↑ 43.3 %	↓ 25%
Gr	↓ 7.4%	↑ 14 %
Nb	↑ 2x	↓ 0.5x



1. HT optimization is fundamental not only for controlling I_c and RRR, but also for mechanical strength.
2. A non-linear trade-off is obtained between the electrical performance and damage threshold due to transverse compressive stress, with a variation in the A15 phase formation dwell time.
3. With a loss in I_c corresponding to 1.7%, a gain of 43% in RRR and 49% in damage threshold in transverse compression may be gained.
4. By reducing the dwell time by ~ 10 h, stronger magnets may be constructed without high compromise on the critical current density.
5. This is essential for future high field [>12 T] magnets, where the conductor is exposed to higher transverse stresses.

THANK YOU!